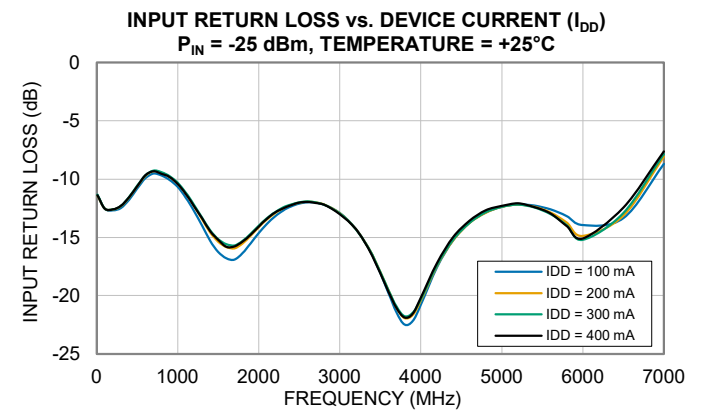
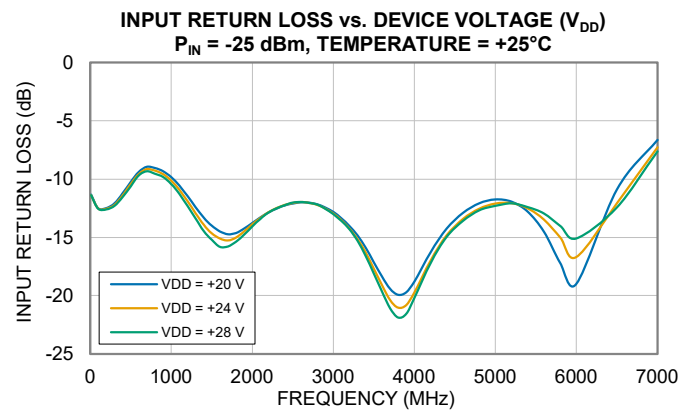
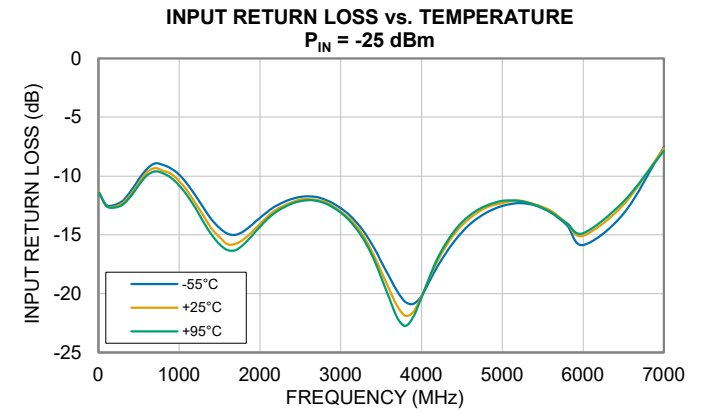
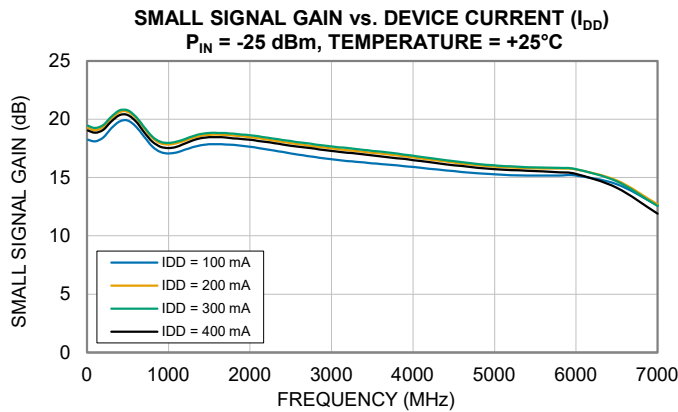
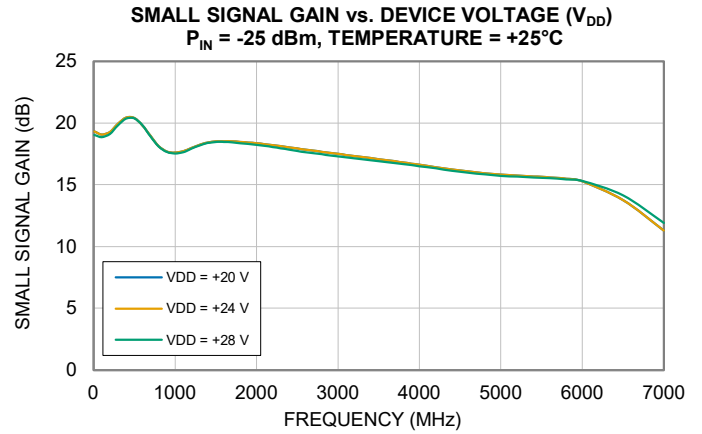
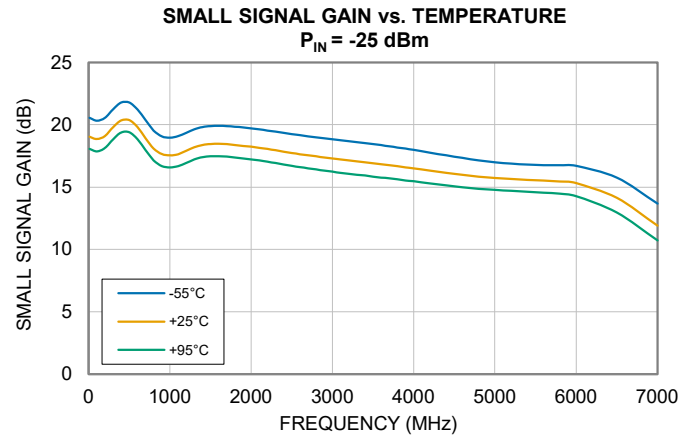


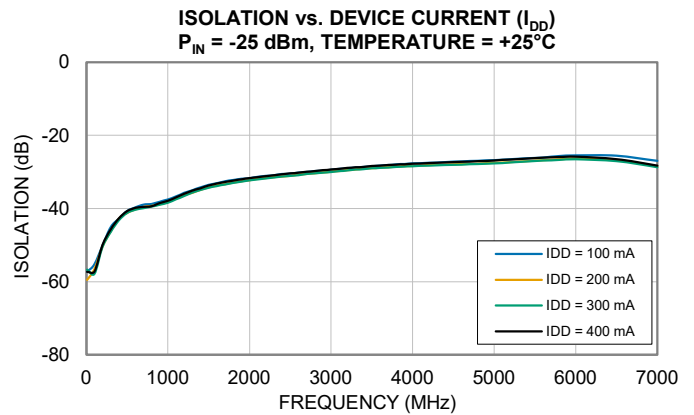
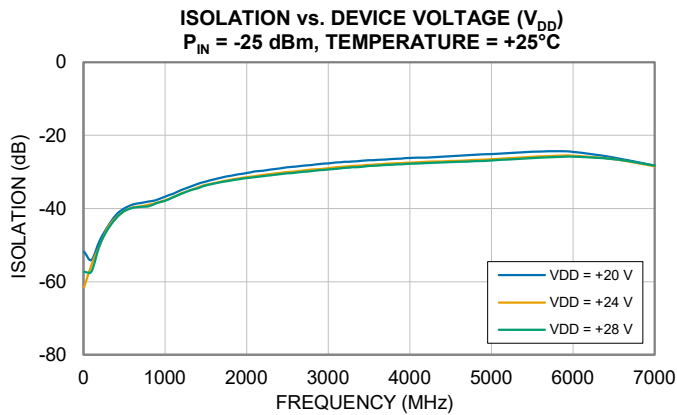
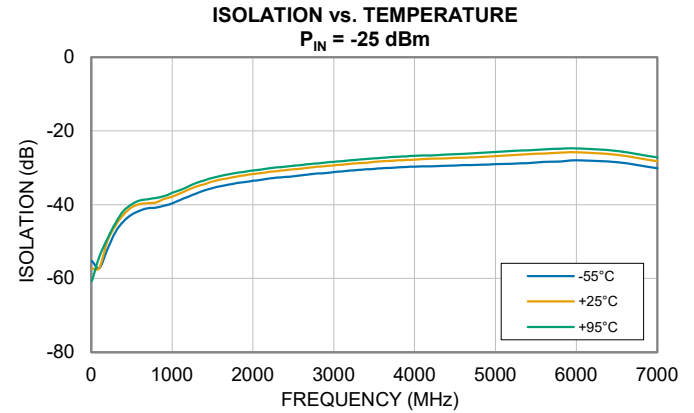
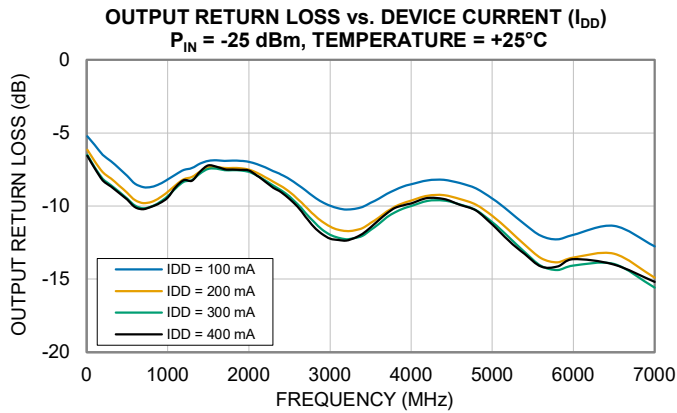
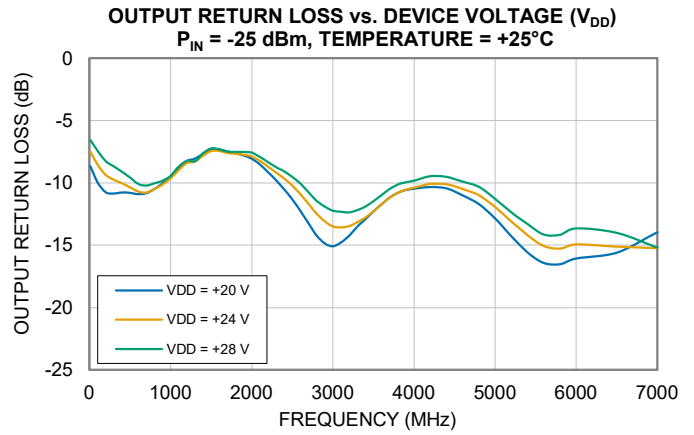
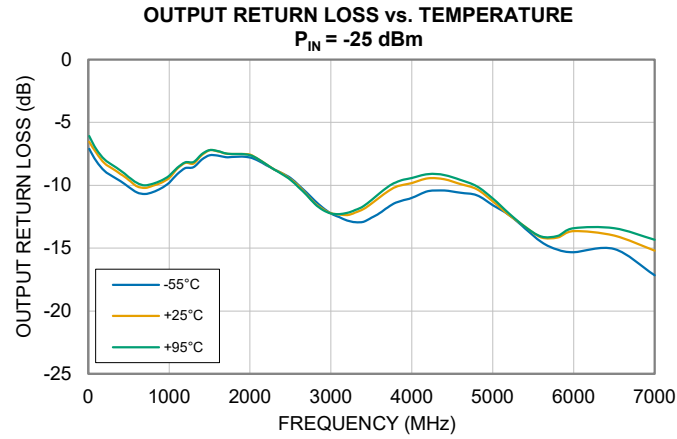
Typical Performance Curves

Note: The following data was taken on Mini-Circuits Characterization Test Board TB-GNA-63-5WCX+ with external bias-T (Figure 2). All data taken at nominal condition of $V_{DD} = +28\text{ V}$ and $I_{DD} = 400\text{ mA}$ unless noted otherwise. V_G was adjusted at each voltage and temperature level to achieve $I_{DD} = 400\text{ mA}$.



Typical Performance Curves

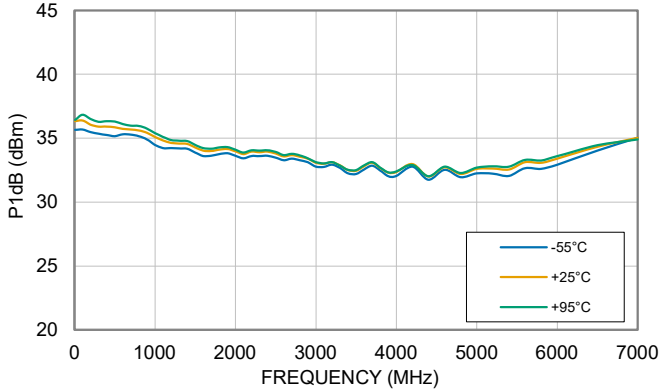
Note: The following data was taken on Mini-Circuits Characterization Test Board TB-GNA-63-5WCX+ with external bias-T (Figure 2). All data taken at nominal condition of $V_{DD} = +28$ V and $I_{DD} = 400$ mA unless noted otherwise. V_G was adjusted at each voltage and temperature level to achieve $I_{DD} = 400$ mA.



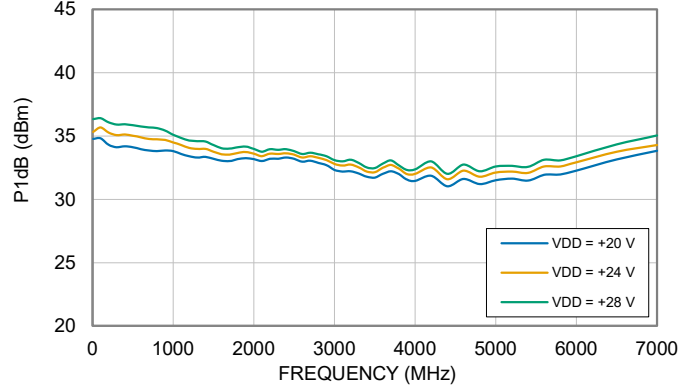
Typical Performance Curves

Note: The following data was taken on Mini-Circuits Characterization Test Board TB-GNA-63-5WCX+ with external bias-T (Figure 2). All data taken at nominal condition of $V_{DD} = +28$ V and $I_{DD} = 400$ mA unless noted otherwise. V_G was adjusted at each voltage and temperature level to achieve $I_{DD} = 400$ mA.

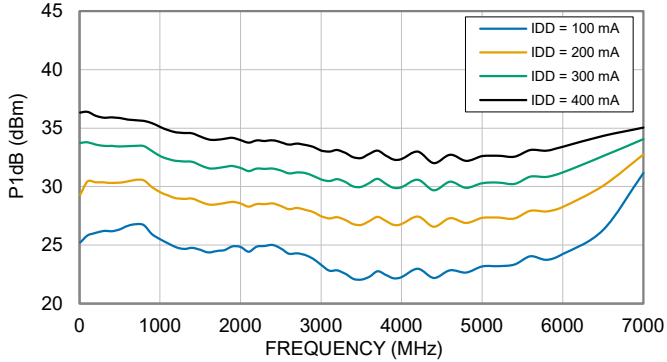
P1dB vs. TEMPERATURE



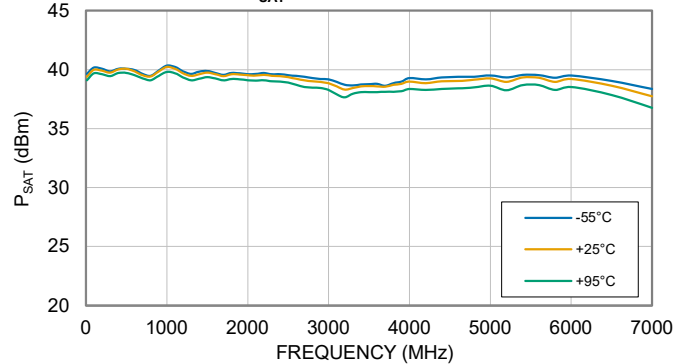
**P1dB vs. DEVICE VOLTAGE (V_{DD})
TEMPERATURE = +25°C**



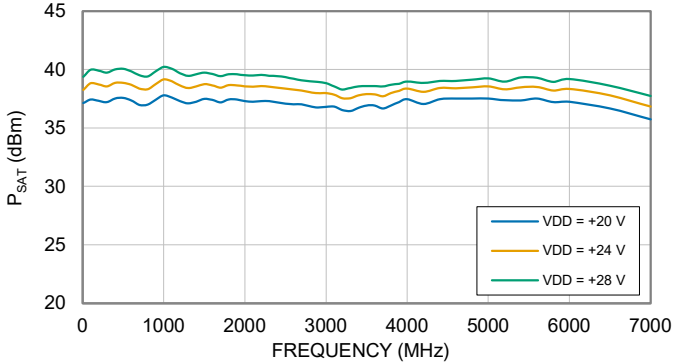
**P1dB vs. DEVICE CURRENT (I_{DD})
TEMPERATURE = +25°C**



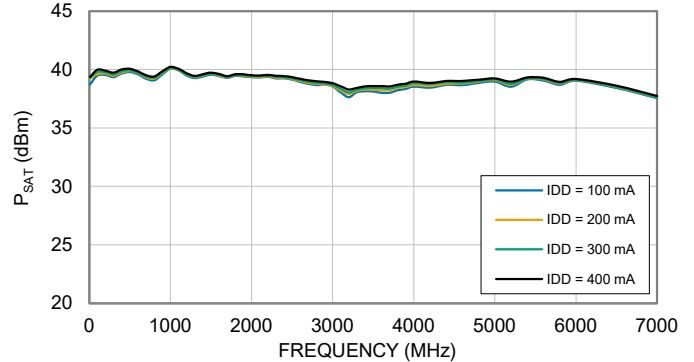
P_{SAT} vs. TEMPERATURE



**P_{SAT} vs. DEVICE VOLTAGE (V_{DD})
TEMPERATURE = +25°C**

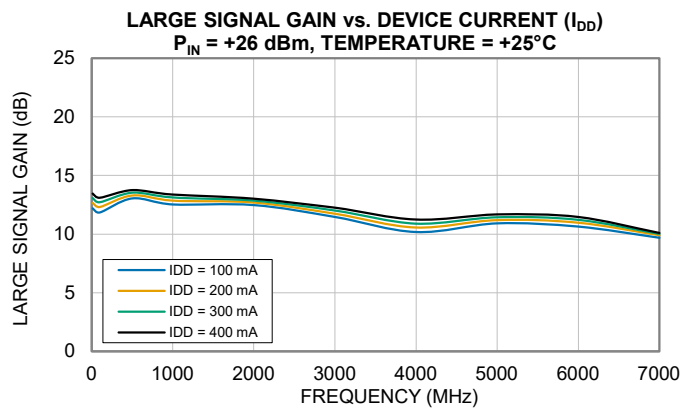
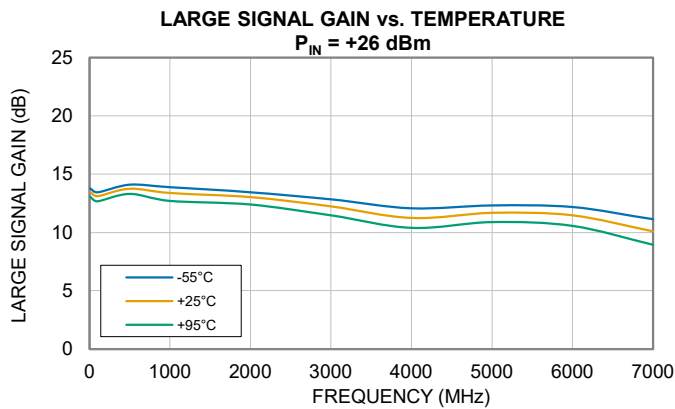
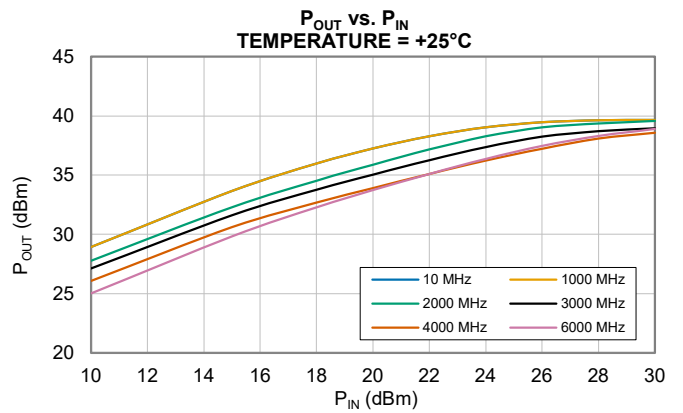
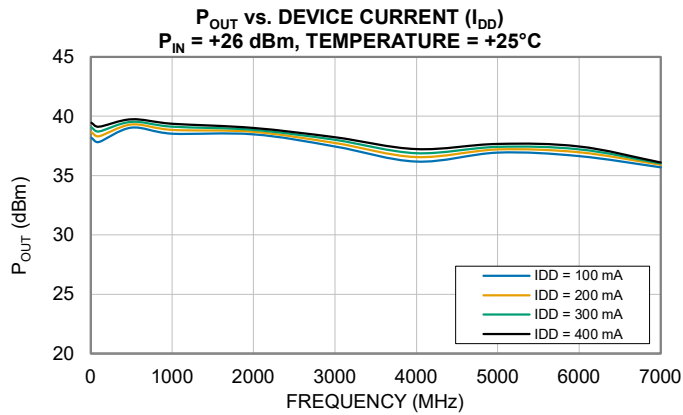
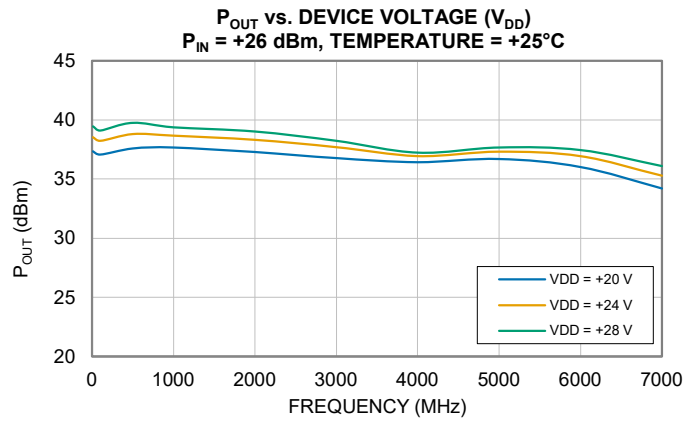
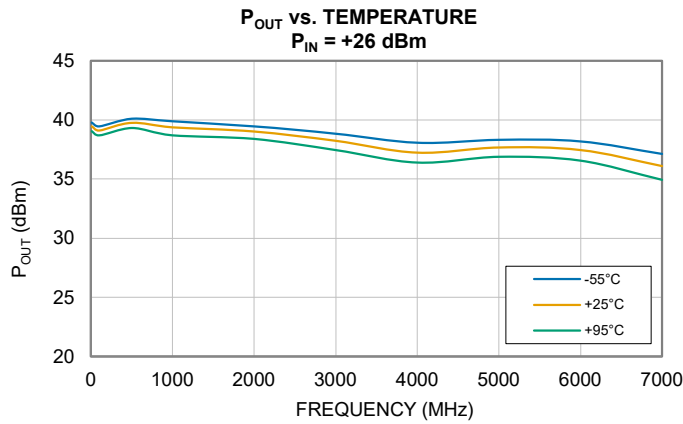


**P_{SAT} vs. DEVICE CURRENT (I_{DD})
TEMPERATURE = +25°C**



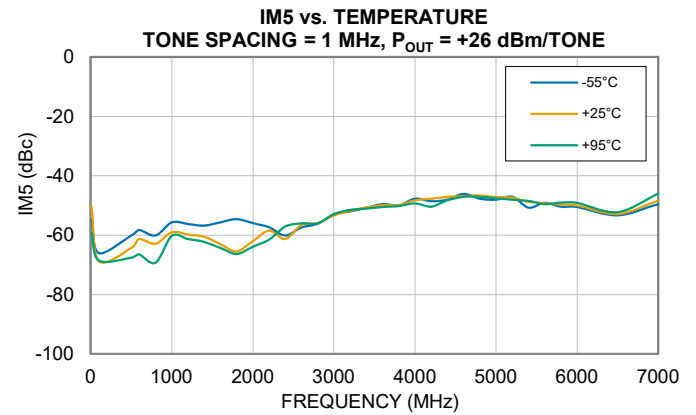
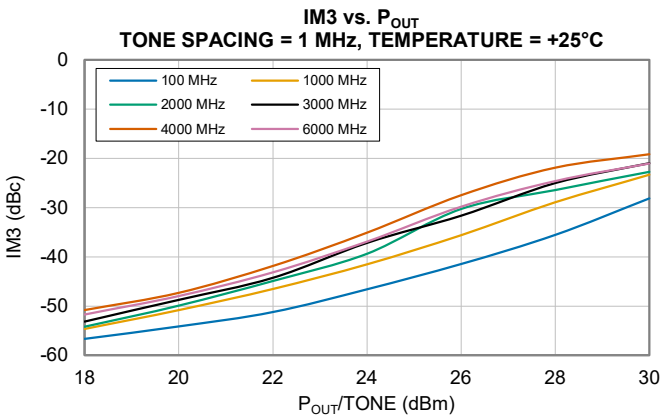
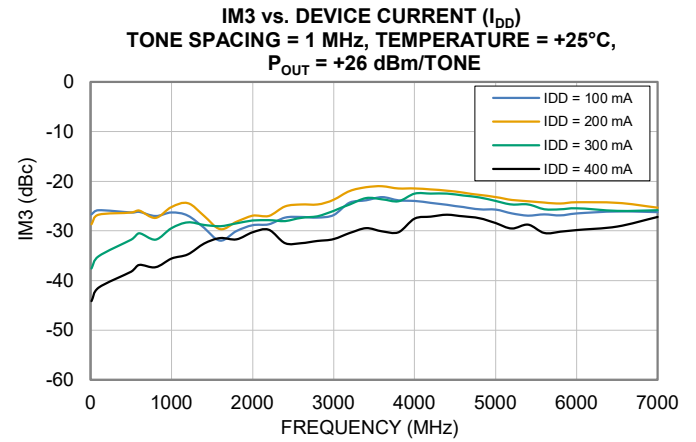
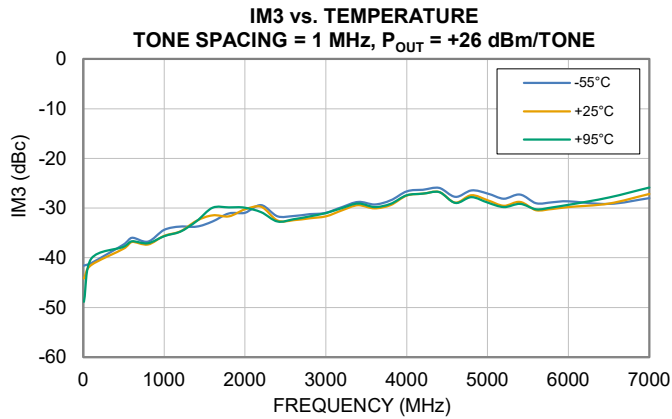
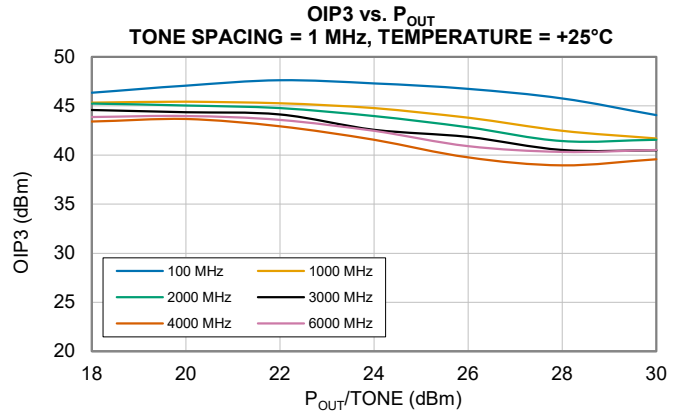
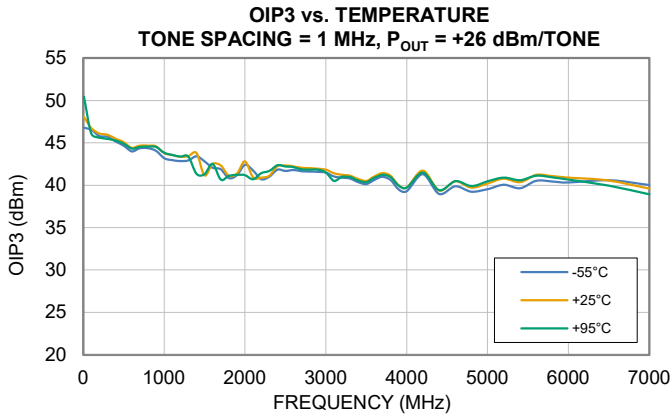
Typical Performance Curves

Note: The following data was taken on Mini-Circuits Characterization Test Board TB-GNA-63-5WCX+ with external bias-T (Figure 2). All data taken at nominal condition of $V_{DD} = +28$ V and $I_{DD} = 400$ mA unless noted otherwise. V_G was adjusted at each voltage and temperature level to achieve $I_{DD} = 400$ mA.



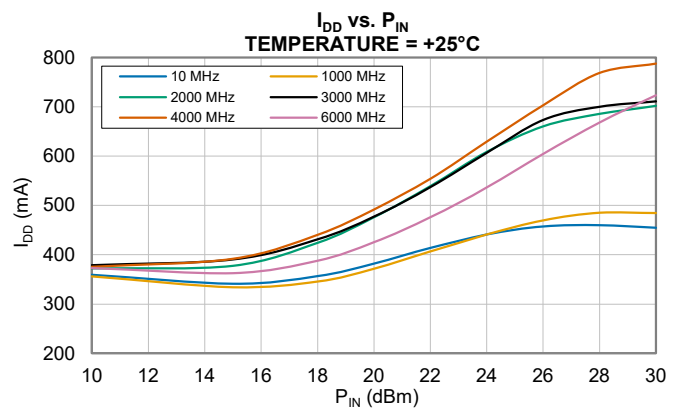
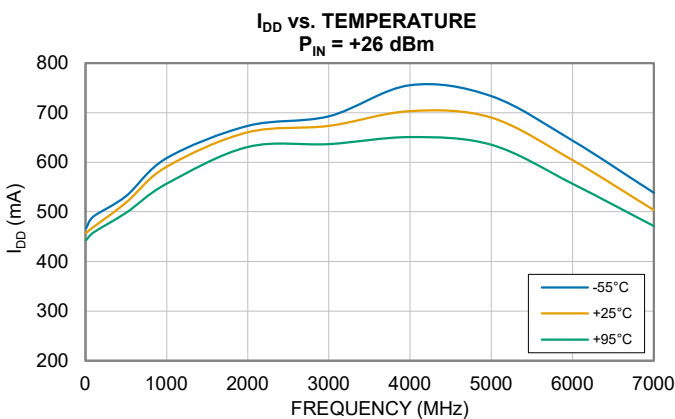
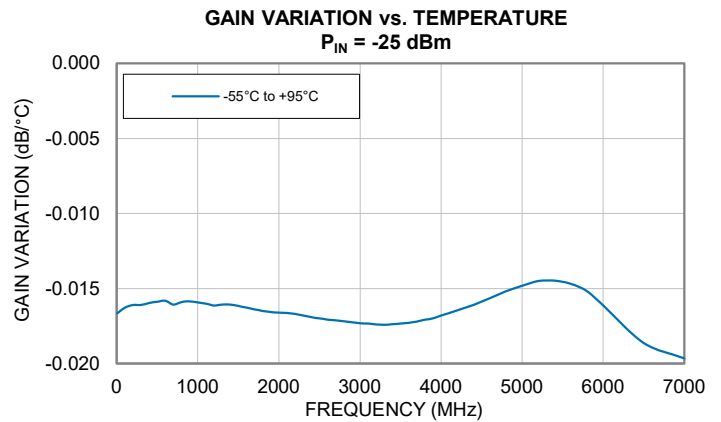
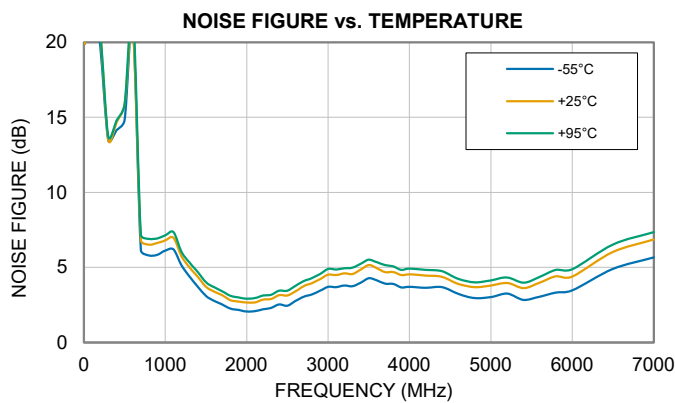
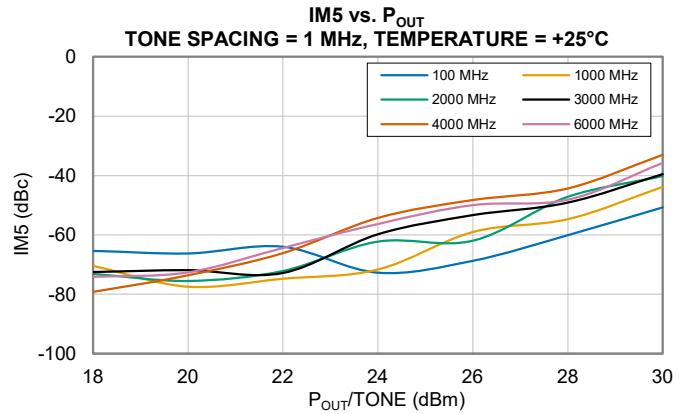
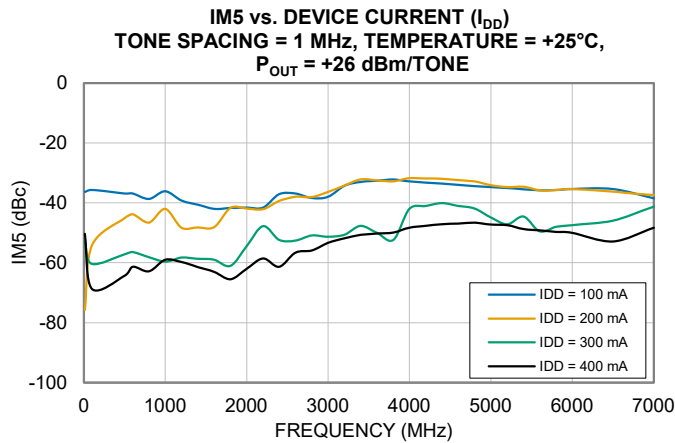
Typical Performance Curves

Note: The following data was taken on Mini-Circuits Characterization Test Board TB-GNA-63-5WCX+ with external bias-T (Figure 2). All data taken at nominal condition of $V_{DD} = +28$ V and $I_{DD} = 400$ mA unless noted otherwise. V_G was adjusted at each voltage and temperature level to achieve $I_{DD} = 400$ mA.



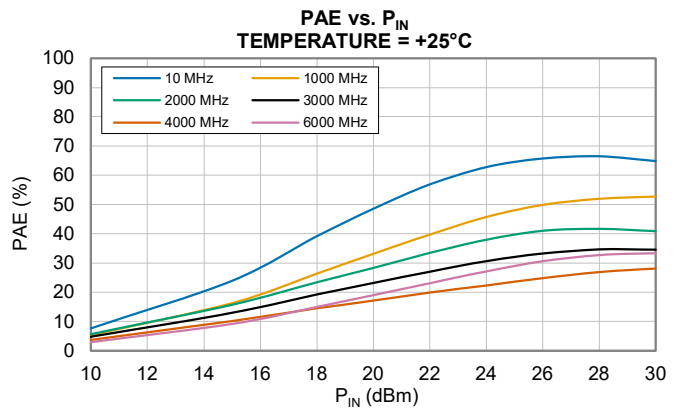
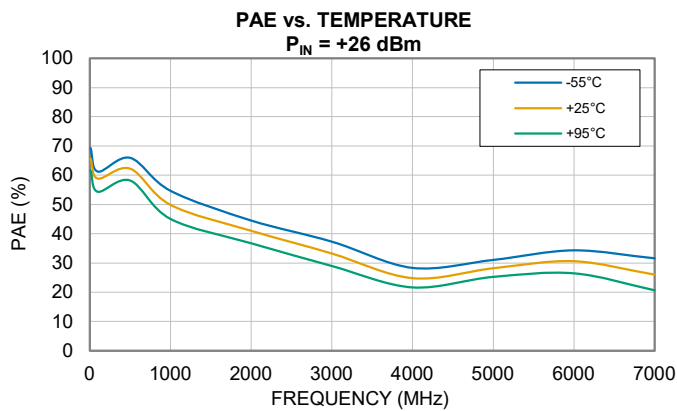
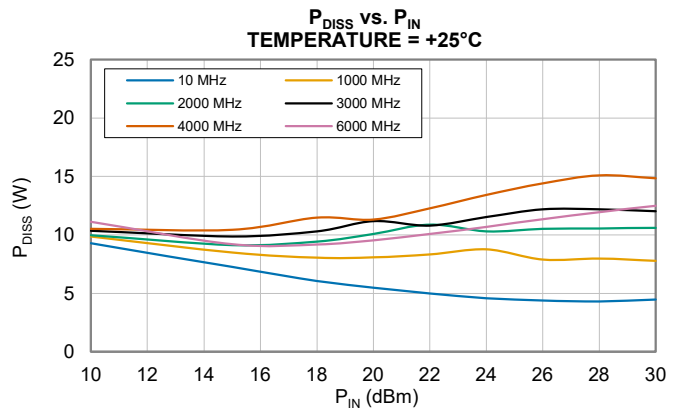
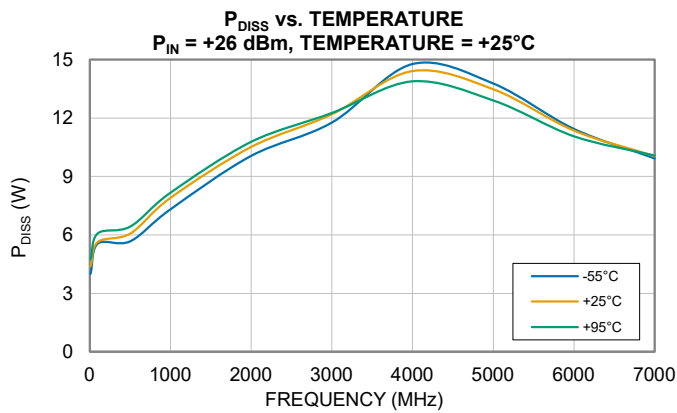
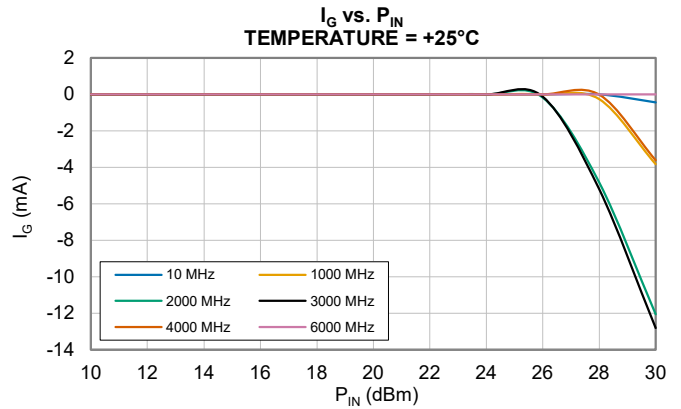
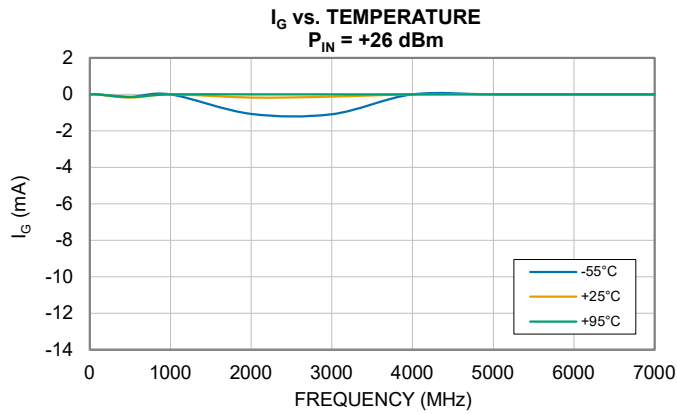
Typical Performance Curves

Note: The following data was taken on Mini-Circuits Characterization Test Board TB-GNA-63-5WCX+ with external bias-T (Figure 2). All data taken at nominal condition of $V_{DD} = +28$ V and $I_{DD} = 400$ mA unless noted otherwise. V_G was adjusted at each voltage and temperature level to achieve $I_{DD} = 400$ mA.



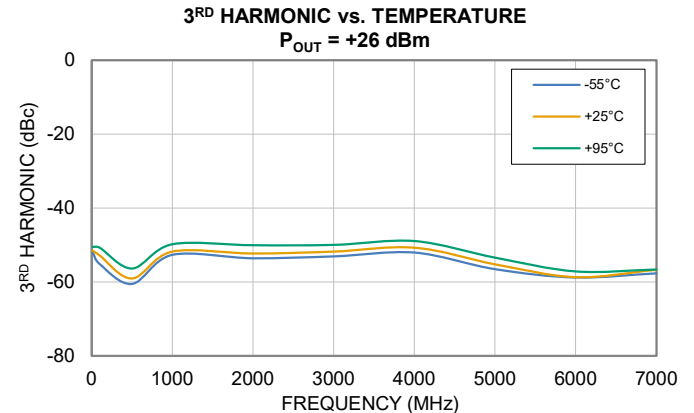
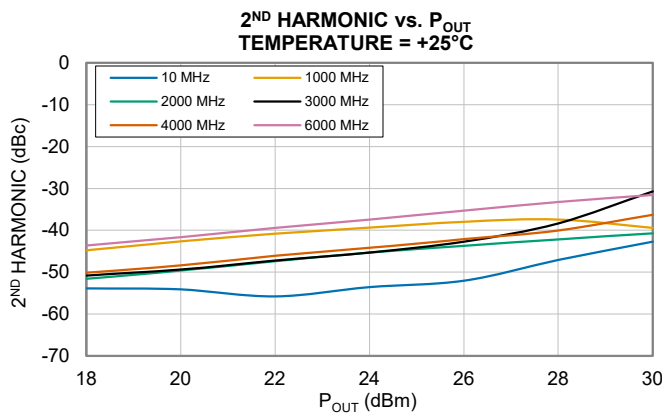
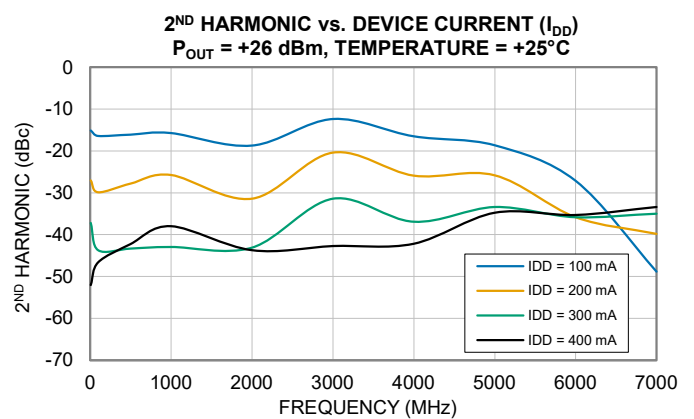
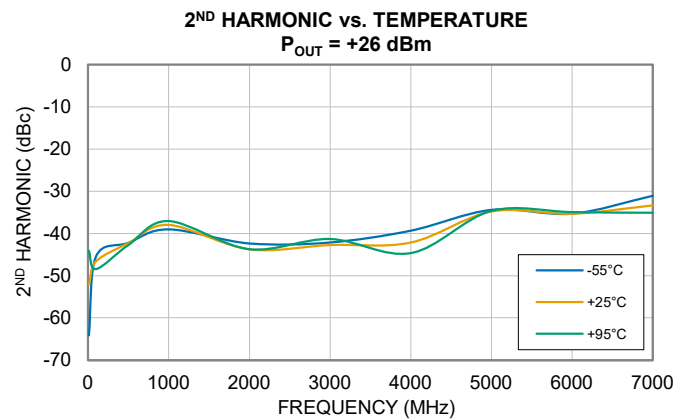
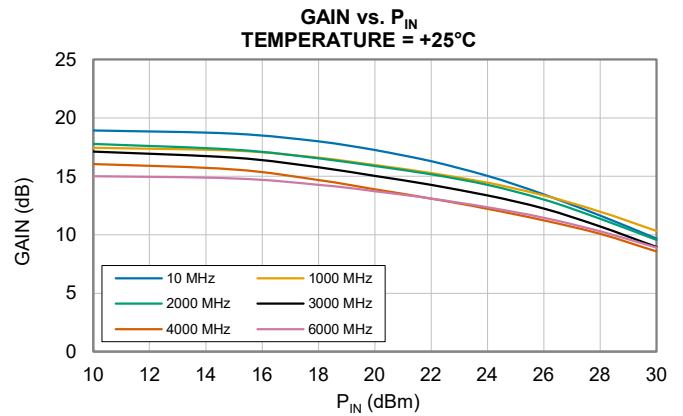
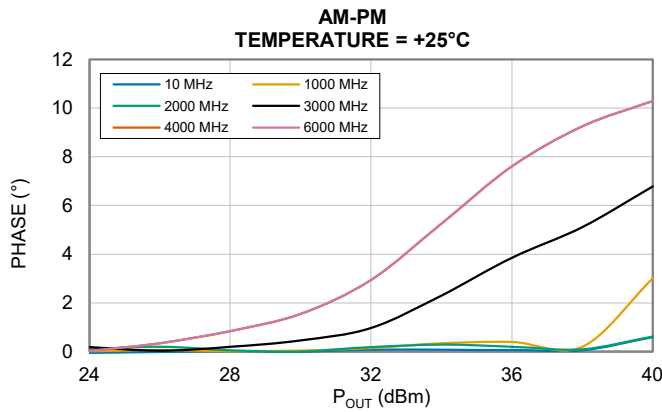
Typical Performance Curves

Note: The following data was taken on Mini-Circuits Characterization Test Board TB-GNA-63-5WCX+ with external bias-T (Figure 2). All data taken at nominal condition of $V_{DD} = +28$ V and $I_{DD} = 400$ mA unless noted otherwise. V_G was adjusted at each voltage and temperature level to achieve $I_{DD} = 400$ mA.



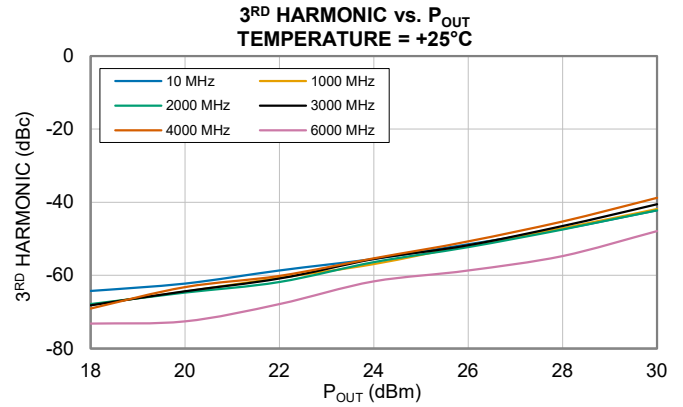
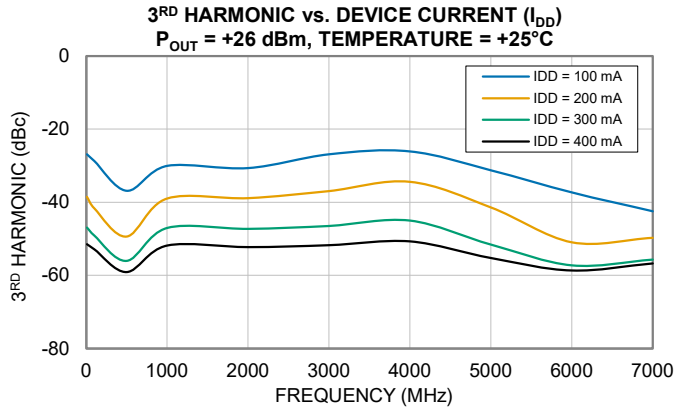
Typical Performance Curves

Note: The following data was taken on Mini-Circuits Characterization Test Board TB-GNA-63-5WCX+ with external bias-T (Figure 2). All data taken at nominal condition of $V_{DD} = +28$ V and $I_{DD} = 400$ mA unless noted otherwise. V_G was adjusted at each voltage and temperature level to achieve $I_{DD} = 400$ mA.



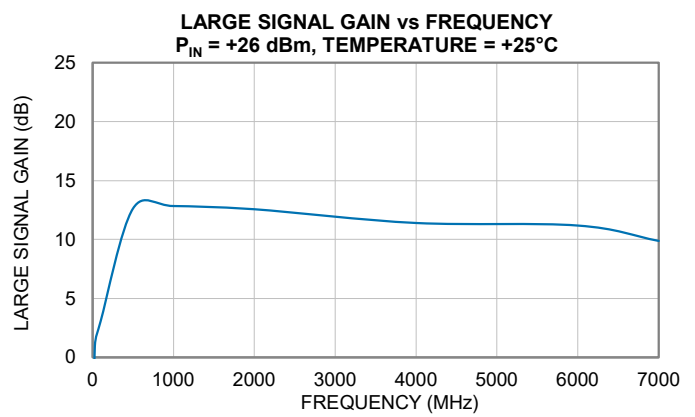
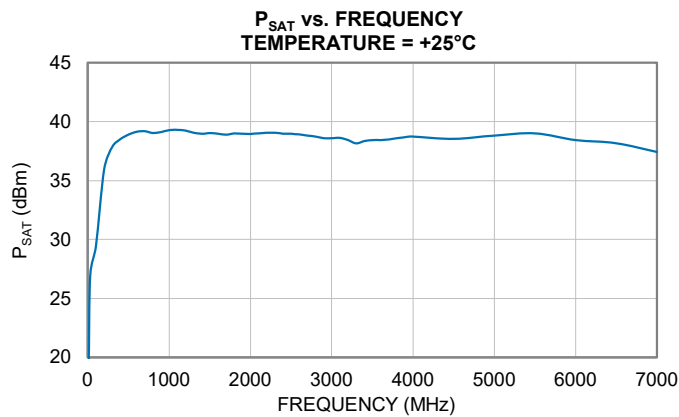
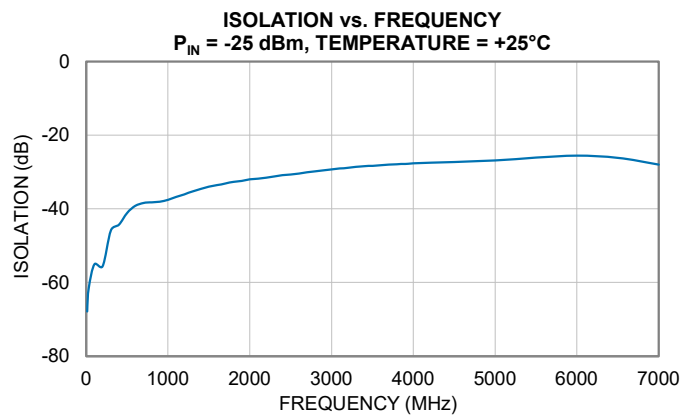
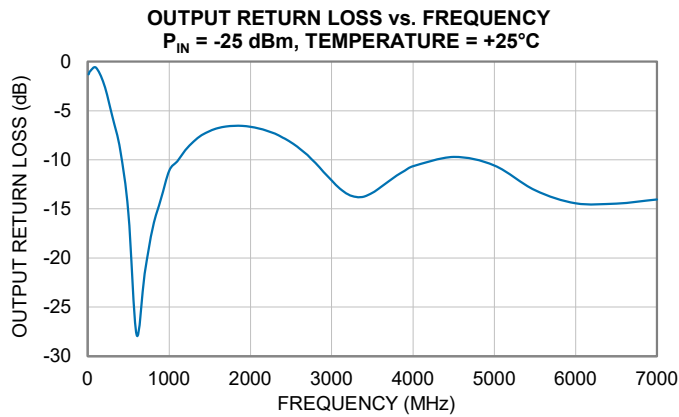
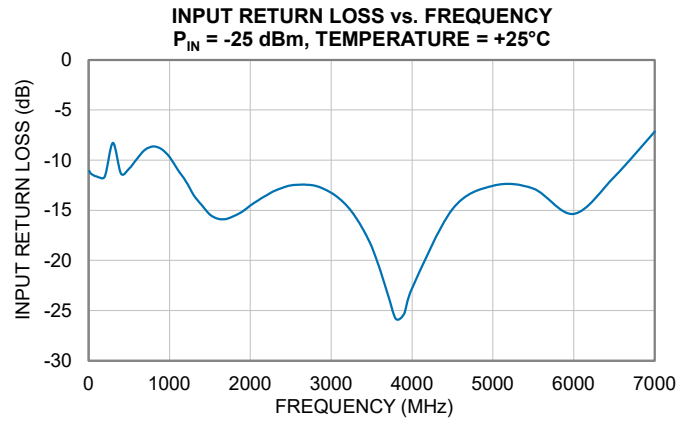
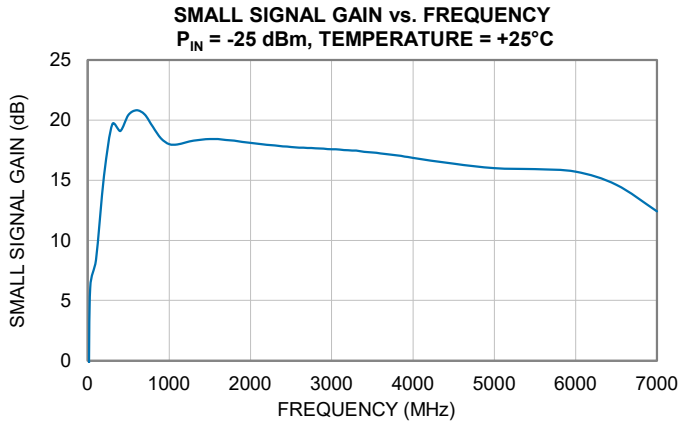
Typical Performance Curves

Note: The following data was taken on Mini-Circuits Characterization Test Board TB-GNA-63-5WCX+ with external bias-T (Figure 2). All data taken at nominal condition of $V_{DD} = +28\text{ V}$ and $I_{DD} = 400\text{ mA}$ unless noted otherwise. V_G was adjusted at each voltage and temperature level to achieve $I_{DD} = 400\text{ mA}$.



Typical Performance Curves

Note: The following data was taken on Mini-Circuits Characterization Test Board TB-GNA-63-5WCX+ (Figure 3). All data taken at nominal condition of $V_{DD} = +28\text{ V}$, $I_{DD} = 400\text{ mA}$, and Temperature = $+25^\circ\text{C}$ unless noted otherwise. V_G was adjusted to achieve $I_{DD} = 400\text{ mA}$.



Typical Performance Curves

Note: The following data was taken on Mini-Circuits Characterization Test Board TB-GNA-63-5WCX+ (Figure 3). All data taken at nominal condition of $V_{DD} = +28\text{ V}$, $I_{DD} = 400\text{ mA}$, and Temperature = $+25^\circ\text{C}$ unless noted otherwise. V_G was adjusted to achieve $I_{DD} = 400\text{ mA}$.

